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Week Date 1/26/04  
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|----------------------|------------------------|--------------------|--------------------|
| a. Serial No.        | f. Foreign Priority    | k. Print Claim(s)  | <u>p. PTO-1449</u> |
| b. Applicant(s)      | g. Disclaimer          | l. Print Fig.      | q. PTOL-85b        |
| c. Continuing Data   | h. Microfiche Appendix | m. Searched Column | r. Abstract        |
| d. PCT               | i. Title               | n. PTO-270/328     | s. Sheets/Figs     |
| e. Domestic Priority | j. Claims Allowed      | o. PTO-892         | t. Other           |

- a. Page Missing
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- h. Sequence Listing
- i. Appendix
- j. Amendments
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① pro-1449 (3 pages): please either initial or line through citations (copy provided for reference).

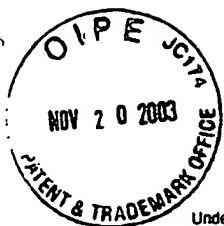
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## RESPONSE

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Substitute for form 1449A/PTO  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)				<b>Complete If Known</b>	
				Application Number	09/653,411
				Filing Date	August 31, 2000
				First Named Inventor	Whonchee Lee
				Art Unit	2815
				Examiner Name	Joseph H. Nguyen
				Attorney Docket Number	M4065.0361/P361
Sheet	1	of	3		

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code* (if known)			
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	AB	2002/0025759	02-28-2002	Lee et al.	
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				First Named Inventor	Whonchee Lee
				Art Unit	2815
				Examiner Name	Joseph H. Nguyen
				Attorney Docket Number	M4065.0361/P361
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Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>2</sup>
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)					
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<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> See attached Kinds Codes of USPTO Patent Documents at [www.uspto.gov](http://www.uspto.gov) or MPEP 901.04. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WFO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the application number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WFO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
	CA	KONDO, S. et al., "Abrasive-Free Polishing for Copper Damascene Interconnection," Journal of the Electrochemical Society, Vol. 147, No. 10, pp. 3907-3913, (2000)	
	CB	D'HEURLE, F.M. and K.C. PARK, IBM Technical Disclosure Bulletin, Electrolytic Process for Metal Pattern Generation, Vol. 17, No. 1, pp. 271-272, June 1974, XP-002235691, NN 7406271.	
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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)				Application Number	09/653.411
				Filing Date	August 31, 2000
				First Named Inventor	Whonchee Lee
				Group Art Unit	2815
				Examiner Name	Joseph H. Nguyen
Sheet	3	of	3	Attorney Docket Number	M4065.0361/P361

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	CE	BASSOUS, E., IBM Technical Disclosure Bulletin, Low Temperature Methods for Rounding Silicon Nozzles, Vol. 20, No. 2, July 1977, pp. 810-811, XP-002235692, NN 7707810.	
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